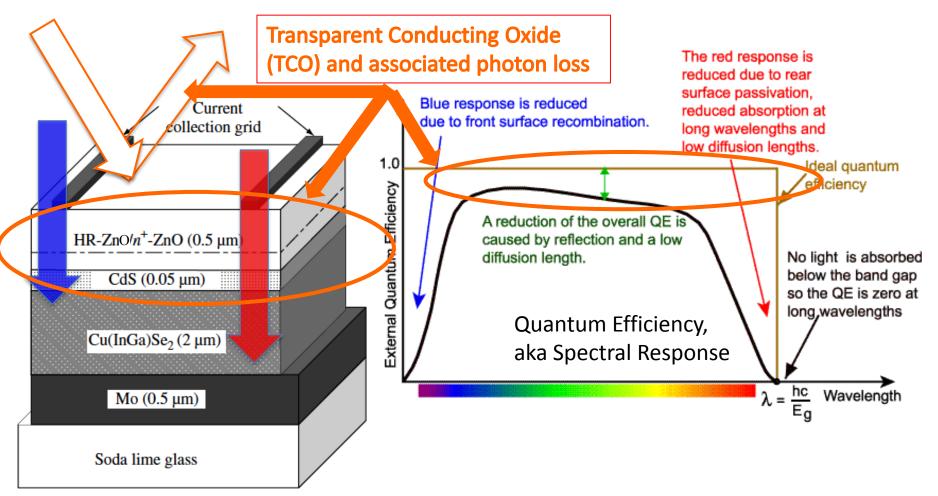
Lab #3 Transparent Conductors

R.J. Ellingson and M.J. Heben

Sept. 17, 2013 PHYS 4580, 6/7280

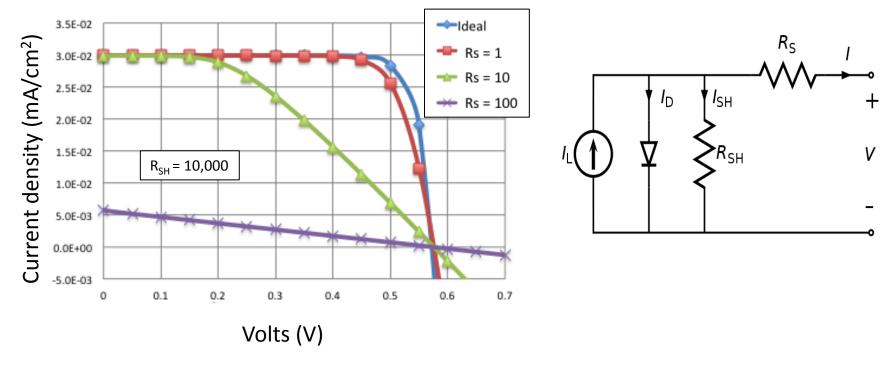
Impact of Optical Loss in Window Layer in PV Cells



Schematic cross section of a typical Cu(InGa)Se₂ solar cell

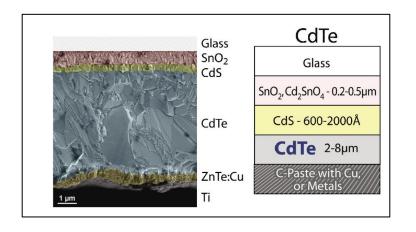
After "Cu(InGa)Se₂ Solar Cells", by Shafarman and Stolt, and PVEducation.org

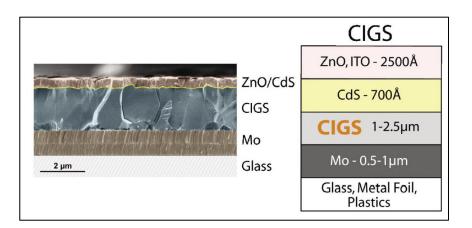
Impact of Electrical Loss Due to High Series Resistance (R_s) PV cells

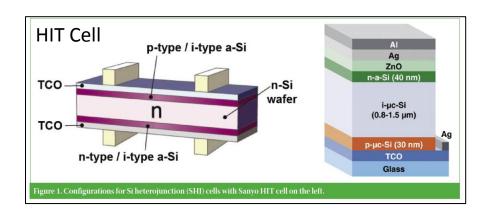


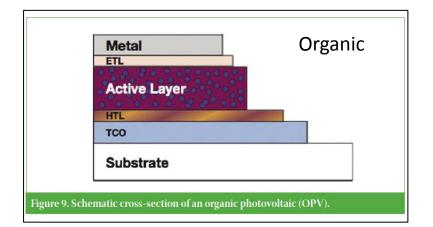
Diode equation with
$$R_s$$
 and R_{SH} : $I = I_L - I_0 \exp\left[\frac{q(V + IR_S)}{nkT}\right] - \frac{V + IR_S}{R_{SH}}$

TCOs are Used in All PV devices









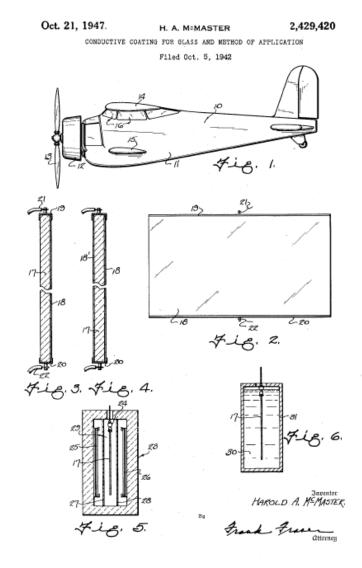
From:

Transparent conducting oxides for advanced photovoltaic applications

John D. Perkins & David S. Ginley, National Renewable Energy Laboratory, Golden, Colorado, USA This paper first appeared in the third print edition of *Photovoltaics International* journal.

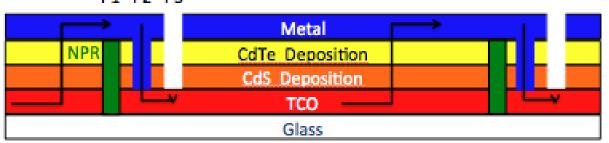
Long History of TCO R&D

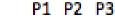
"It is an object of this invention to provide on glass or other electrically non-conductive surfaces thin transparent coatings or films possessing the property of electrical conductivity, which coatings are clear, hard and tenacious and of uniform thickness; which are in intimate contact with the glass or other surface; and which will retain these properties under adverse conditions" – Harold McMaster

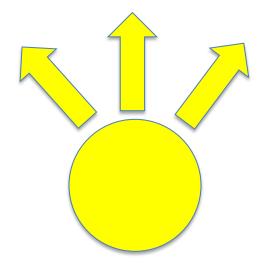


Monolithically Integrated TF Module

The balance between electrical conductivity and optical transparency becomes even more important when current and photons are to be collected over large areas, as is the case in a module.^{*}

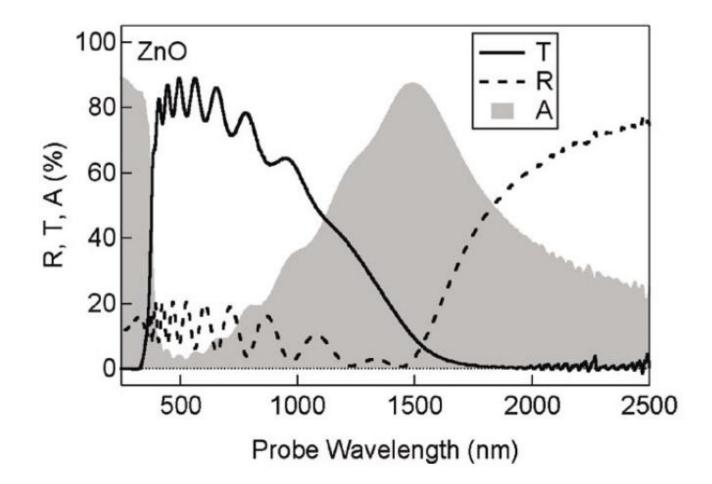






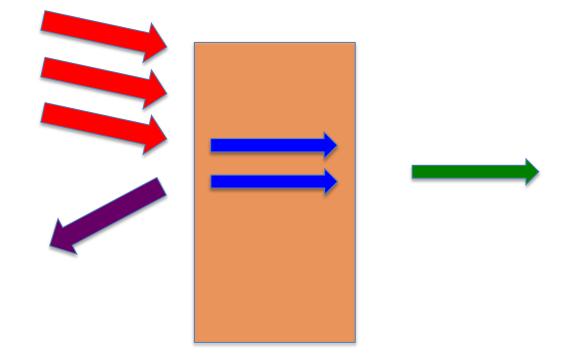
Manufacturability
is also a big
concern!!

Typical Reflection, Transmission, and Absorption Data



From: Perkins and Ginley

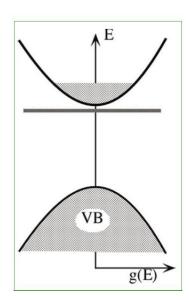
Total Incident (λ) = A(λ) + T(λ)+ R(λ)

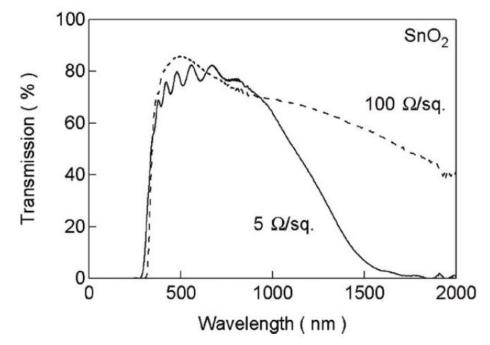


Conservation of Energy for each wavelength

Defect Equilibria and Doping in TCOs

- TCO materials are typically wide band gap oxides that are degeneratively doped via defect or substitutional chemistry.
- The trade off between electrical conductivity and transparency is due to the interplay between the electronic structure of the material and the doping.





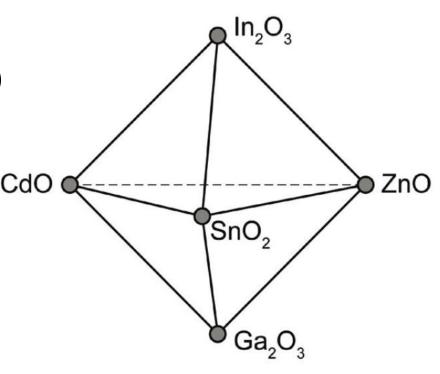
From: Perkins and Ginley

Phase Space for Engineering the Properties of TCOs

"Conventional" compositional space

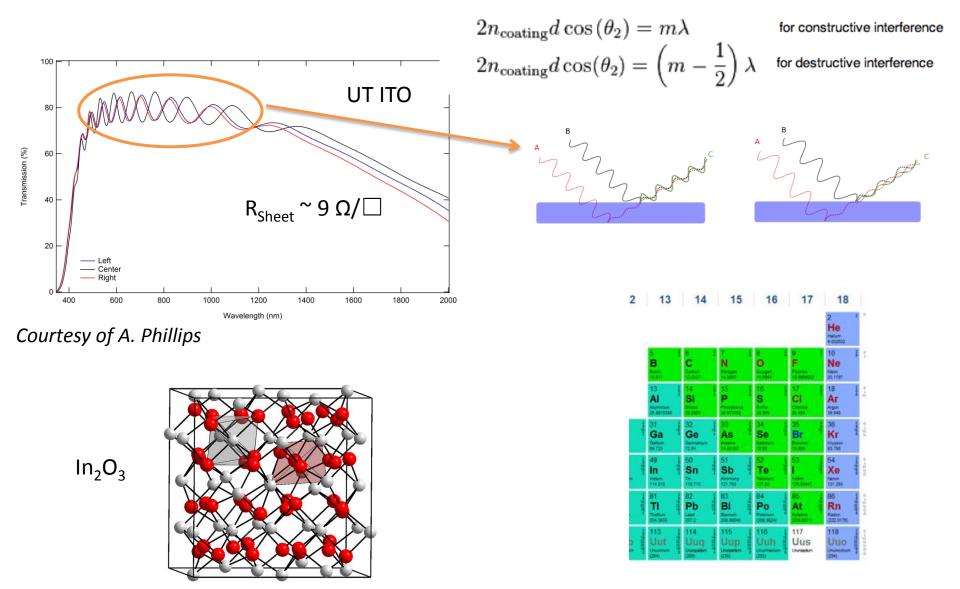
Additional Parameters for control:

- Compositional alloys (e.g. Cd₂SnO₄₎
- Dopants on the anion sublattice (i.e. FTO)
- Dopants on the cation sublattice (e.g., ITO)
- Defect equilibria on oxygen subattice
- New materials
- Nanomaterials (non-oxides, e.g. singlewall carbon nanotubes, metal nano wires, composites, etc.



$O_O^x \leftrightarrow V_O^{\bullet \bullet} + 0.5O_2(g) + 2e'$

ITO – Tin doped Indium Oxide



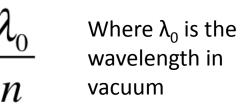
http://en.wikipedia.org/wiki/Thin-film_interference

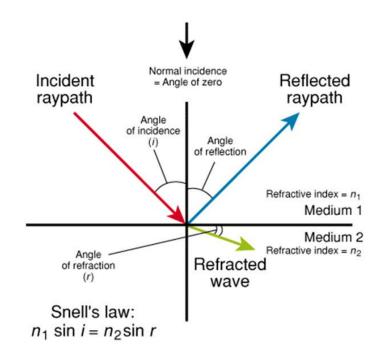
Snell's Law and the Index of Refraction

n, the Index of Refraction, aka Refractive Index

- Describes how light propagates in a medium.
- Is a dimensionless number.
- The speed of light in a medium is reduced:

$$v_{ph} = \frac{c}{n}$$
 $v = \frac{c}{\lambda}$





Although named after Dutch astronomer **Willebrord Snellius** (1580–1626), the law was first accurately described by the scientist **Ibn Sahl** at Baghdad court, when in 984 he used the law to derive lens shapes that focus light with no geometric aberrations in the manuscript *On Burning Mirrors and Lenses*

Absorption

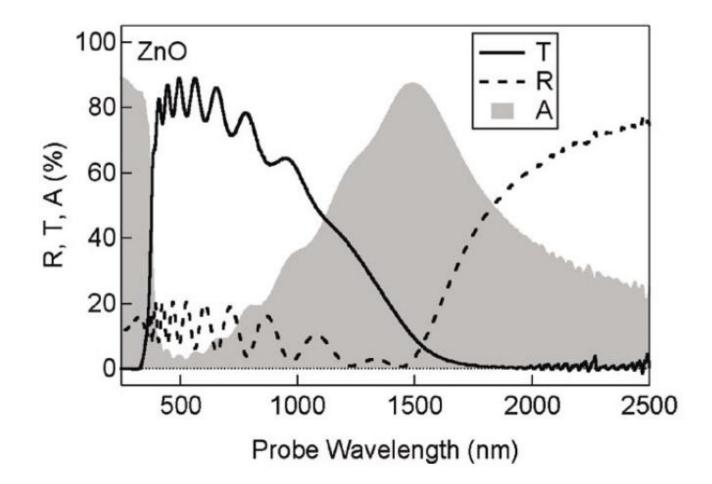
- Up to now, we have considered only the Index of Refraction, n.
- This is enough when there is no absorption (e.g., wide band gap oxides interacting with sub-band gap light).
- In general, we must consider refraction, reflection and and absorption, and a complex index:

$$\tilde{n} = n + i\kappa$$

• Here, n is still the Index of Refraction, and reflects the phase speed of the light in the medium, but *κ* now refers to the amount of absorption loss.

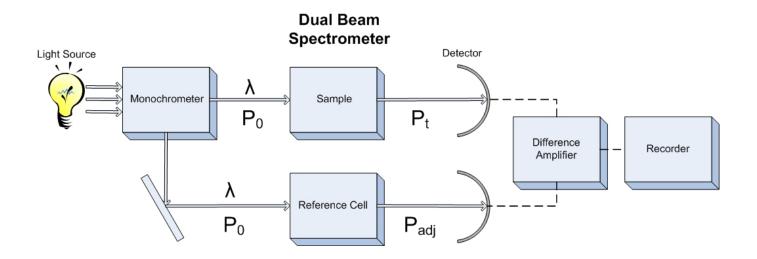
$$\alpha = \frac{4\pi\kappa}{\lambda} \qquad \qquad \frac{I}{I_0} = e^{-\alpha x}$$

Typical Reflection, Transmission, and Absorption Data



From: Perkins and Ginley

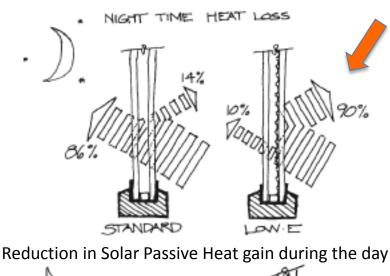
Conventional Dual Beam Spectrophotometer

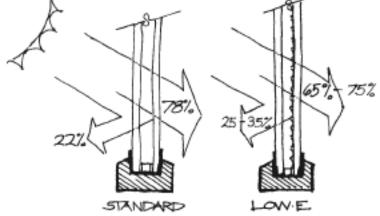


In this Lab, we are building a Single Beam Spectrophotometer

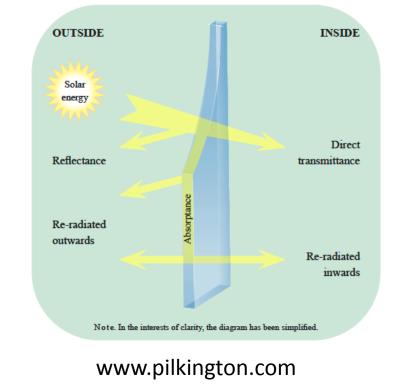
http://chemwiki.ucdavis.edu

TCO Coatings on Glass Facilitate High Efficiency window technology





Reflection of long wavelength light at night is a big deal!

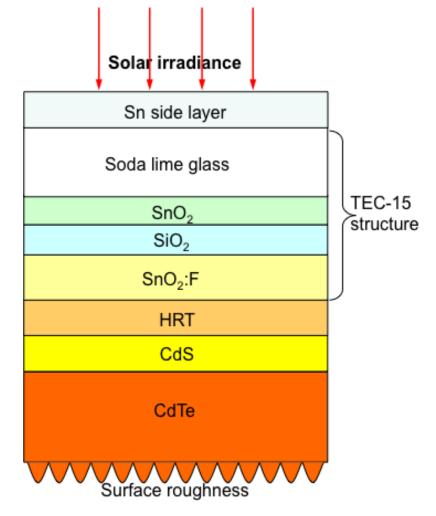


"Consumer's guide to buying energy-efficient windows and doors" by Canada's Office of Energy Efficiency Learn about how a Float Line Works at: http://www.youtube.com/watch?v=OVokYKqWRZE

TEC Coatings are Complex

The TEC-15 glass:

- Thick soda-lime float glass (3.2 mm)
- > Thin SnO₂ layer (~300 Å)
- SiO₂ layer (~200 Å)
- SnO₂:F layer (~3000 Å)
- Thick HRT (~850 Å)



Courtesy of Prakash Koirala

Different kinds of TEC products

TEC Glass[™] portfolio

TEC 7

Offers the lowest resistivity value in the TEC Glass[™] range. Combined with relatively low haze, it can be used for a wide range of applications including dye solar cells, electromagnetic shielding and thin film photovoltaics.

TEC 8

Designed for use specifically with amorphous silicon thin film photovoltaics. This product combines the low resistivity of **TEC 7** with a high haze coating required for good conversion efficiencies of amorphous silicon modules.

TEC 15

The best choice for applications requiring passive condensation control and thermal performance with low emissivity and clear color-neutral appearance.

TEC 35

For use in heated glass applications, this product combines thermal control with superior electro-optical properties.

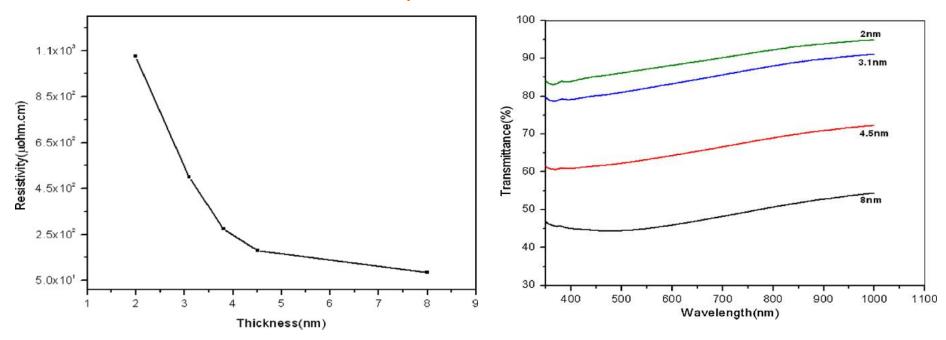
http://www.cytodiagnostics.com

Ultrathin chromium transparent metal contacts by pulsed dc magnetron sputtering

K. V. Rajani*,¹, S. Daniels¹, P. J. McNally², F. Olabanji Lucas², and M. M. Alam²

¹Nanomaterials Processing Laboratory, National Centre for Plasma Science and Technology (NCPST), School of Electronic Engineering, Dublin City University, Dublin 9, Ireland

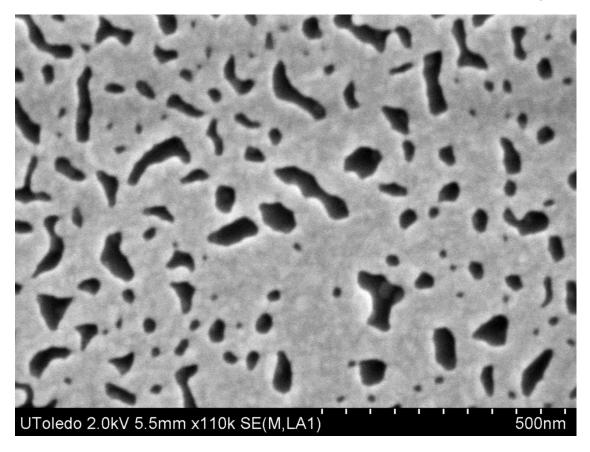
Thin metal films can also be transparent



"The sheet resistance values corresponding to the 2, 3.1, 4.5 and 8 nm thick films are 5×10^3 , 1.6×10^3 , 4×10^2 and $1 \times 10^2 \Omega / \Box$, respectively."

Phys. Status Solidi A 207, No. 7, 1586–1589 (2010) / DOI 10.1002/pssa.200983732

Sheet Resistance – importance of film morphology



Scanning Electron Microscope (SEM) image of ~15 nm thick Au deposited by thermal evaporation.